查询TL780-05CKTE供应商



Internal Short-Circuit Current Limiting

Pinout Identical to µA7800 Series

Improved Version of µA7800 Series

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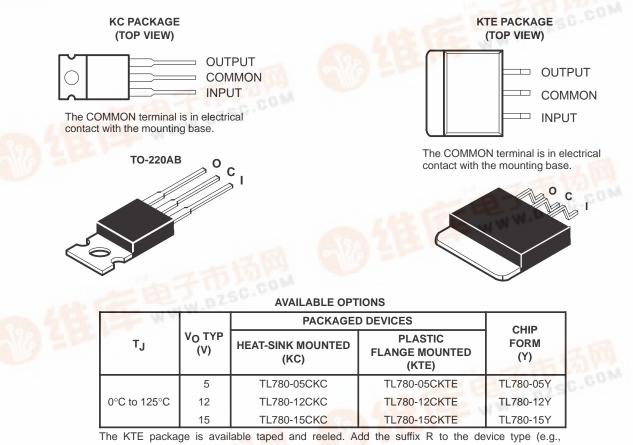
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- ±1% Output Tolerance at 25°C
- ±2% Output Tolerance Over Full Operating Range
- Thermal Shutdown

description

Each fixed-voltage precision regulator in the TL780 series is capable of supplying 1.5 A of load current. A unique temperature-compensation technique, coupled with an internally trimmed band-gap reference, has resulted in improved accuracy when compared to other three-terminal regulators. Advanced layout techniques provide excellent line, load, and thermal regulation. The internal current-limiting and thermal-shutdown features make the devices essentially immune to overload.

The TL780-xxC series regulators are characterized for operation over the virtual junction temperature range of 0°C to 125°C.



TL780-05CKTER). Chip forms are tested at 25°C.

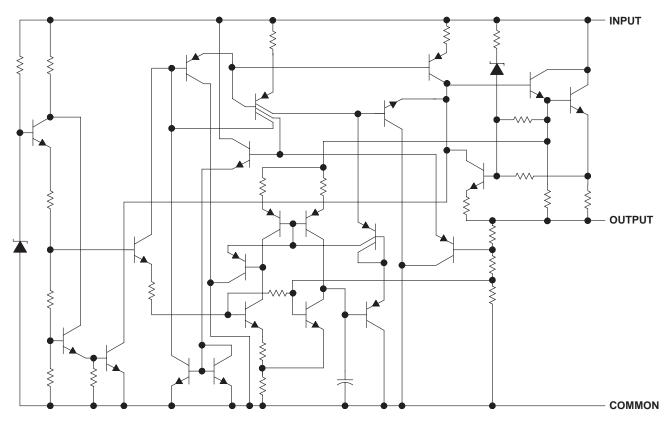


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schematic





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absolute maximum ratings over operating temperature range (unless otherwise noted)[†]

Input voltage, V _I	35 V
Package thermal impedance, θ_{JA} (see Notes 1 and 2): KC package	22°C/W
KTE package	23°C/W
Operating free-air, T _A ; case, T _C ; or virtual junction, T _J , temperature range	. 0°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C
Storage temperature range, T _{stg}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. Maximum power dissipation is a function of $T_J(max)$, θ_{JA} , and T_A . The maximum allowable power dissipation at any allowable ambient temperature is $P_D = (T_J(max) - T_A)/\theta_{JA}$. Operating at the absolute maximum T_J of 150°C can impact reliability. Due to variations in individual device electrical characteristics and thermal resistance, the built-in thermal overload protection may be activated at power levels slightly above or below the rated dissipation.

2. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions

			MAX	UNIT
	TL780-05C	7	25	
Input voltage, VI	TL780-12C	14.5	30	V
	TL780-15C	17.5	30	
Output current, IO			1.5	А
Operating virtual junction temperature, TJ			125	°C

electrical characteristics at specified virtual junction temperature, $V_I = 10 V$, $I_O = 500 mA$ (unless otherwise noted)

PARAMETER	TEST CONDITIONS	- +	TL780-05C			LINUT
PARAMETER	TEST CONDITIONS	t_⊺	MIN	TYP	MAX	UNIT
	$I_{O} = 5 \text{ mA to 1 A}, P \le 15 \text{ W},$	25°C	4.95	5	5.05	v
Output voltage	$V_{I} = 7 V \text{ to } 20 V$	0°C to 125°C	4.9		5.1	v
	$V_I = 7 V \text{ to } 25 V$	25°C		0.5	5	
Input voltage regulation	VI = 8 V to 12 V	25°C		0.5	5	mV
Ripple rejection	V _I = 8 V to 18 V, f = 120 Hz	0°C to 125°C	70	85		dB
Output voltage regulation	I _O = 5 mA to 1.5 A	25%0		4	25	mV
	I _O = 250 mA to 750 mA	25°C		1.5	15	
Output resistance	f = 1 kHz	0°C to 125°C		0.0035		W
Temperature coefficient of output voltage	I _O = 5 mA	0°C to 125°C		0.25		mV/°C
Output noise voltage	f = 10 Hz to 100 kHz	25°C		75		μV
Dropout voltage	I _O = 1 A	25°C		2		V
Input bias current		25°C		5	8	mA
	V _I = 7 V to 25 V	000 to 40500		0.7	1.3	
nput bias-current change	$I_{O} = 5 \text{ mA to 1 A}$	0°C to 125°C		0.003 0.5		mA
Short-circuit output current		25°C		750		mA
Peak output current		25°C		2.2		A

⁺ Pulse-testing techniques maintain the junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33-μF capacitor across the input and a 0.22-μF capacitor across the output.



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electrical characteristics at specified virtual junction temperature, V_I = 19 V, I_O = 500 mA (unless otherwise noted)

PARAMETER	TEST CONDITIONS		т _J †	TL780-12C			UNIT	
PARAMETER	TEST CONDITION	TEST CONDITIONS		MIN	TYP	MAX	UNIT	
Output veltogo	$I_{O} = 5 \text{ mA to 1 A}, P \le 15 \text{ W},$	≤ 15 W,	25°C	11.88	12	12.12	V	
Output voltage	VI = 14.5 V to 27 V		0°C to 125°C	11.76		12.24	v	
Insuit voltage regulation	VI = 14.5 V to 30 V		25°C		1.2	12	mV	
Input voltage regulation	VI = 16 V to 22 V				1.2	12	mv	
Ripple rejection	VI = 15 V to 25 V, f =	120 Hz	0°C to 125°C	65	80		dB	
	IO = 5 mA to 1.5 A		0500		6.5	60		
Dutput voltage regulation $I_{O} = 250 \text{ mA to } 750 \text{ mA}$ 25°C	25-0		2.5	36	mV			
Output resistance	f = 1 kHz		0°C to 125°C		0.0035		W	
Temperature coefficient of output voltage	IO = 5 mA		0°C to 125°C		0.6		mV/°C	
Output noise voltage	f = 10 Hz to 100 kHz		25°C		180		μV	
Dropout voltage	I _O = 1 A		25°C		2		V	
Input bias current			25°C		5.5	8	mA	
lanut higo gurrant ghanga	VI = 14.5 V to 30 V	000 1- 4050			0.4	1.3		
nput bias-current change	$I_{O} = 5 \text{ mA to 1 A}$		0°C to 125°C		0.03	0.5	mA	
Short-circuit output current			25°C		350		mA	
Peak output current			25°C		2.2		А	

[†] Pulse-testing techniques maintain the junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33-μF capacitor across the input and a 0.22-μF capacitor across the output.

electrical characteristics at specified virtual junction temperature, $V_I = 23 V$, $I_O = 500 mA$ (unless otherwise noted)

PARAMETER	TEST CONDITIONS	- +	TL780-15C				
PARAMETER	TEST CONDITIONS	TJ [†]	MIN	TYP	MAX	UNIT	
	$I_{O} = 5 \text{ mA to 1 A}, \qquad P \le 15 \text{ W},$	25°C	14.85	15	15.15	v	
Output voltage	V _I = 17.5 V to 30 V	0°C to 125°C	14.7		15.3	v	
Innut voltogo regulation	$V_{I} = 17.5 V \text{ to } 30 V$	25%0		1.5	15		
Input voltage regulation	$V_{I} = 20 V \text{ to } 26 V$	25°C		1.5	15	mV	
Ripple rejection	V _I = 18.5 V to 28.5 V, f = 120 Hz	0°C to 125°C	60	75		dB	
	IO = 5 mA to 1.5 A	25°C		7	75	mV	
Output voltage regulation	I _O = 250 mA to 750 mA			2.5	45		
Output resistance	f = 1 kHz	0°C to 125°C		0.0035		W	
Temperature coefficient of output voltage	IO = 5 mA	0°C to 125°C		0.62		mV/°C	
Output noise voltage	f = 10 Hz to 100 kHz	25°C		225		μV	
Dropout voltage	I _O = 1 A	25°C		2		V	
Input bias current		25°C		5.5	8	mA	
	V _I = 17.5 V to 30 V	000 to 10500		0.4	1.3		
nput bias-current change	$I_{O} = 5 \text{ mA to 1 A}$	0°C to 125°C		0.02	0.5	mA	
Short-circuit output current		25°C		230		mA	
Peak output current		25°C		2.2		A	

[†] Pulse-testing techniques maintain the junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33-μF capacitor across the input and a 0.22-μF capacitor across the output.



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electrical characteristics, V_I = 10 V, I_O = 500 mA, T_J = 25°C (unless otherwise noted)

PARAMETER		TL780-05Y	
PARAMETER	TEST CONDITIONS [†]	MIN TYP N	AAX UNIT
Output voltage	$I_{O} = 5 \text{ mA to 1 A}, \qquad P \le 15 \text{ W}$	5	V
Insuit voltage regulation	$V_{I} = 7 V \text{ to } 25 V$	0.5	mV
Input voltage regulation	$V_I = 8 V$ to 12 V	0.5	mv
	$I_{O} = 5 \text{ mA to } 1.5 \text{ A}$	4	mV
Output voltage regulation	$I_{O} = 250 \text{ mA to } 750 \text{ mA}$	1.5	mv
Output noise voltage	f = 10 Hz to 100 kHz	75	μV
Dropout voltage	I _O = 1 A	2	V
Input bias current		5	mA
Short-circuit output current		750	mA
Peak output current		2.2	A

[†] Pulse-testing techniques maintain the junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33-μF capacitor across the input and a 0.22-μF capacitor across the output.

electrical characteristics, V_I = 19 V, I_O = 500 mA, T_J = 25°C (unless otherwise noted)

PARAMETER	TEST CONDITIONS [†]	MIN	TYP	MAX	UNIT	
Output voltage	$I_{O} = 5 \text{ mA to 1 A}, \qquad P \le 15 \text{ W}$		12		V	
	V _I = 14.5 V to 30 V	1.2				
Input voltage regulation	$V_I = 16 V \text{ to } 22 V$		mV			
Output voltage regulation	I _O = 5 mA to 1.5 A	6.5			mV	
Output voltage regulation	I _O = 250 mA to 750 mA		2.5	IIIV		
Output noise voltage	f = 10 Hz to 100 kHz		180		μV	
Dropout voltage	I _O = 1 A		2		V	
Input bias current			5.5		mA	
Short-circuit output current			350		mA	
Peak output current			2.2		А	

⁺ Pulse-testing techniques maintain the junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33-μF capacitor across the input and a 0.22-μF capacitor across the output.



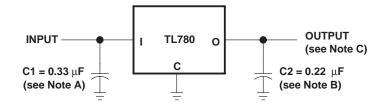
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electrical characteristics, $V_I = 23 V$, $I_O = 500 mA$, $T_J = 25^{\circ}C$ (unless otherwise noted)

DADAMETED		TL780-15Y		
PARAMETER	TEST CONDITIONS [†]	MIN TYP MAX	UNIT	
Output voltage	$I_{O} = 5 \text{ mA to 1 A}, \qquad P \le 15 \text{ W}$	15	V	
Input voltage regulation	V _I = 17.5 V to 30 V	1.5		
	V _I = 20 V to 26 V	1.5	mV	
Output voltage regulation	$I_{O} = 5 \text{ mA to } 1.5 \text{ A}$	7	mV	
	I _O = 250 mA to 750 mA	2.5		
Output resistance	f = 1 kHz	0.0035	W	
Output noise voltage	f = 10 Hz to 100 kHz	225	μV	
Dropout voltage	I _O = 1 A	2	V	
Input bias current		5.5	mA	
Short-circuit output current		230	mA	
Peak output current		2.2	A	

[†] Pulse-testing techniques maintain the junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33-μF capacitor across the input and a 0.22-μF capacitor across the output.

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C1 is required when the regulator is far from the power-supply filter.

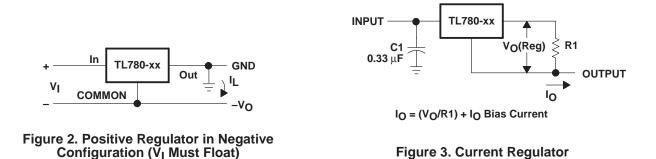
- B. C2 is not required for stability; however, transient response is improved.
 - C. Permanent damage can occur when OUTPUT is pulled below ground.

Figure 1. Test Circuit



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APPLICATION INFORMATION



operation with a load common to a voltage of opposite polarity

In many cases, a regulator powers a load that is not connected to ground but, instead, is connected to a voltage source of opposite polarity (e.g., operational amplifiers, level-shifting circuits, etc.). In these cases, a clamp diode should be connected to the regulator output as shown in Figure 4. This protects the regulator from output polarity reversals during startup and short-circuit operation.

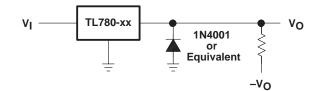


Figure 4. Output Polarity-Reversal-Protection Circuit

reverse-bias protection

Occasionally, the input voltage to the regulator can collapse faster than the output voltage. This, for example, could occur when the input supply is crowbarred during an output overvoltage condition. If the output voltage is greater than approximately 7 V, the emitter-base junction of the series pass element (internal or external) could break down and be damaged. To prevent this, a diode shunt can be employed, as shown in Figure 5.

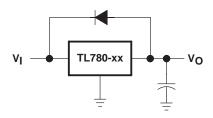


Figure 5. Reverse-Bias-Protection Circuit



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